

NOTES:

1. SUBSTRATE: UV GRADE FUSED SILICA
2. SURFACE S2 TO BE PARALLEL WITH SURFACE S1 TO WITHIN <30 arcsec
3. COATING (APPLY ACROSS COATING APERTURE)

DURABILITY: MIL-C-48497A, SECT. 3.4.1

PERFORMANCE SPECIFICATIONS: @ 0° AOI

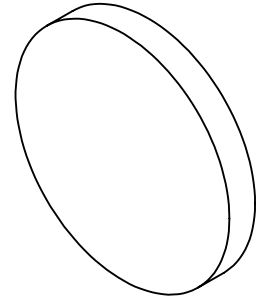
T(avg): ≥91% FROM 425 - 860nm

T(avg): ≤0.01% FROM 905 - 1220nm

CUT-OFF SLOPE: <1%

CUT-OFF WAVELENGTH: 875nm ± 1%

**FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING**

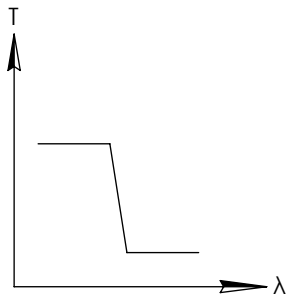
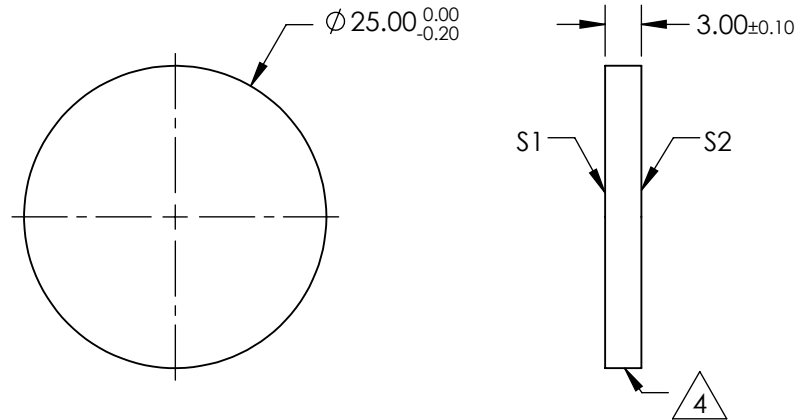


4. FINE GRIND SURFACE

5. POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS
APPLY ACROSS CLEAR APERTURE

6. TRANSMITTED WAVEFRONT DISTORTION RMS@ 632.8nm ≤ ¼ λ

7. ROHS COMPLIANT



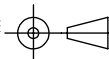
SHORTPASS FILTER

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

EO® Edmund Optics®

	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	40-20	40-20
CLEAR APERTURE	>80%	>80%
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE
PROJECTION



ALL DIMS IN

mm

TITLE

OD4, Ø25mm, 875nm, SHORTPASS FILTER

DWG NO

86106

SHEET
1 OF 1